FOR IMMEDIATE RELEASE

Contacts:

Aehr Test Systems
Steve Steps
Senior Director
(510) 623-9400

Financial Relations Board:
Amy Cozamanis
Analyst/Investor Contact
(310) 854-8314

Laurie Berman
General Inquiries
(310) 854-8315

AEHR TEST SYSTEMS RECEIVES PRODUCTION ORDER FOR FOX FULL WAFER TEST SYSTEM

Fremont, CA (April 27, 2005) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced that a leading semiconductor manufacturer has placed a production order for the Company's new 300mm FOX™ full wafer contact test and burn-in system. The order is valued in excess of $1.0 million.

"We are very pleased to get the first production order for our new 300mm FOX system," said Greg Perkins, vice president of worldwide sales and service of Aehr Test. "This is the second order overall for our 300mm FOX system and we expect additional follow on orders from this customer, a leading memory manufacturer. We expect to ship both systems later this calendar year."

"The market potential of the new 300mm FOX system is very exciting," said Rhea Posedel, chairman and chief executive officer of Aehr Test. "There are many applications for this system, ranging from test to short-duration burn-in. We believe our innovative solution, which combines full wafer contact with Design For Test (DFT), will create a very high throughput solution with a very low cost of test per device."

About Aehr Test Systems
Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology, acceptance by customers of the FOX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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